

May 2001

FQP50N06L

60V LOGIC N-Channel MOSFET

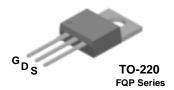
General Description

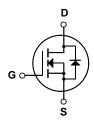
These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for low voltage applications such as automotive, DC/ DC converters, and high efficiency switching for power management in portable and battery operated products.

Features

- 52.4A, 60V, $R_{DS(on)} = 0.021\Omega$ @V_{GS} = 10 V Low gate charge (typical 24.5 nC)
- Low Crss (typical 90 pF)
- Fast switching
- 100% avalanche tested
- Improved dv/dt capability
- 175°C maximum junction temperature rating





Absolute Maximum Ratings T_C = 25°C unless otherwise noted

Symbol	Parameter		FQP50N06L	Units
V _{DSS}	Drain-Source Voltage		60	V
I _D	Drain Current - Continuous (T _C = 25°	°C)	52.4	А
	- Continuous (T _C = 100°C)		37.1	А
I _{DM}	Drain Current - Pulsed	(Note 1)	210	А
V _{GSS}	Gate-Source Voltage		± 20	V
E _{AS}	Single Pulsed Avalanche Energy	(Note 2)	990	mJ
I _{AR}	Avalanche Current	(Note 1)	52.4	А
E _{AR}	Repetitive Avalanche Energy	(Note 1)	12.1	mJ
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	7.0	V/ns
P_{D}	Power Dissipation (T _C = 25°C)		121	W
	- Derate above 25°C		0.81	W/°C
T _J , T _{STG}	Operating and Storage Temperature Range		-55 to +175	°C
T _L	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	°C

Thermal Characteristics

Symbol	Parameter	Тур	Max	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case		1.24	°C/W
$R_{\theta CS}$	Thermal Resistance, Case-to-Sink	0.5		°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient		62.5	°C/W

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Cha	aracteristics					
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	60			V
ΔBV_{DSS} / ΔT_J	Breakdown Voltage Temperature Coefficient	I _D = 250 μA, Referenced to 25°C		0.06		V/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 60 V, V _{GS} = 0 V			1	μΑ
		V _{DS} = 48 V, T _C = 150°C			10	μΑ
I _{GSSF}	Gate-Body Leakage Current, Forward	V _{GS} = 20 V, V _{DS} = 0 V			100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	V _{GS} = -20 V, V _{DS} = 0 V			-100	nA
On Cha	racteristics					
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu\text{A}$	1.0		2.5	V
R _{DS(on)}	Static Drain-Source	V _{GS} = 10 V, I _D = 26.2 A		0.017	0.021	•
' DS(on)	On-Resistance	V _{GS} =5V, I _D =26.2A		0.020	0.021	Ω
9 _{FS}	Forward Transconductance	V _{DS} = 25 V, I _D = 26.2 A (Note 4)		40		S
Dynami	ic Characteristics			T		
C _{iss}	Input Capacitance	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$		1250	1630	pF
Coss	Output Capacitance	f = 1.0 MHz		445	580	pF
C _{rss}	Reverse Transfer Capacitance			90	120	pF
Switchi	ing Characteristics					
t _{d(on)}	Turn-On Delay Time	V 20 V I 20 0 A		20	50	ns
t _r	Turn-On Rise Time	$V_{DD} = 30 \text{ V}, I_D = 26.2 \text{ A},$		380	770	ns
t _{d(off)}	Turn-Off Delay Time	$R_G = 25 \Omega$		80	170	ns
t _f	Turn-Off Fall Time	(Note 4, 5)		145	300	ns
Q _g	Total Gate Charge	V _{DS} = 48 V, I _D = 52.4 A,		24.5	32	nC
Q _{gs}	Gate-Source Charge	$V_{GS} = 5 \text{ V}$		6		nC
Q _{gd}	Gate-Drain Charge	(Note 4, 5)		14.5		nC
	Source Diode Characteristics a	nd Maximum Ratings	ı			
I _S	Maximum Continuous Drain-Source Diode Forward Current				52.4	Α
I _{SM}	Maximum Pulsed Drain-Source Diode Forward Current				210	Α
V_{SD}	Drain-Source Diode Forward Voltage	V _{GS} = 0 V, I _S = 52.4 A			1.5	٧
t _{rr}	Reverse Recovery Time	V _{GS} = 0 V, I _S = 52.4 A,		65		ns
Q _{rr}	Reverse Recovery Charge	$dI_F / dt = 100 A/\mu s$ (Note 4)		125		nC

- Notes: 1. Repetitive Rating : Pulse width limited by maximum junction temperature 2. L = 300μ H, I_{AS} = 52.4A, V_{DD} = 25V, R_{G} = $25~\Omega$, Starting T_{J} = 25° C 3. $I_{SD} \le 52.4A$, di/dt $\le 300A/\mu$ s, $V_{DD} \le BV_{DSS}$, Starting T_{J} = 25° C 4. Pulse Test : Pulse width $\le 300\mu$ s, Duty cycle $\le 2\%$ 5. Essentially independent of operating temperature

Typical Characteristics

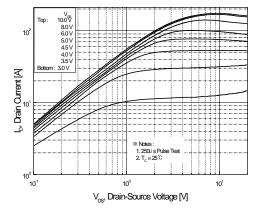


Figure 1. On-Region Characteristics

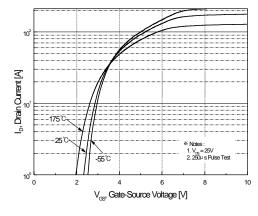


Figure 2. Transfer Characteristics

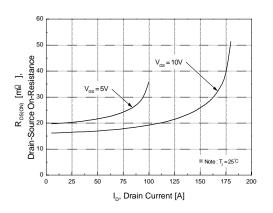


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

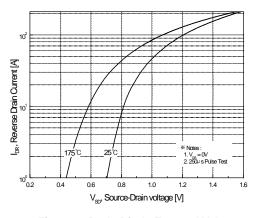


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

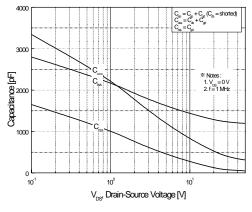


Figure 5. Capacitance Characteristics

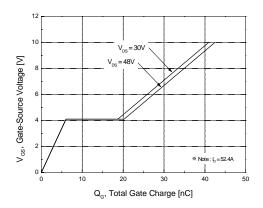
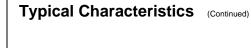


Figure 6. Gate Charge Characteristics

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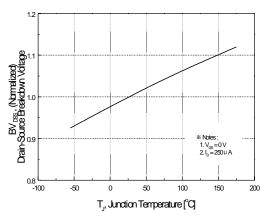


Figure 7. Breakdown Voltage Variation vs. Temperature

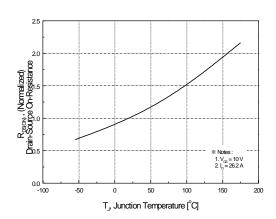


Figure 8. On-Resistance Variation vs. Temperature

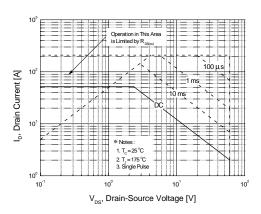


Figure 9. Maximum Safe Operating Area

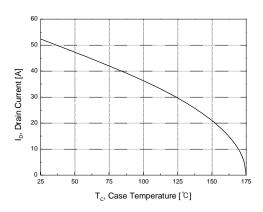


Figure 10. Maximum Drain Current vs. Case Temperature

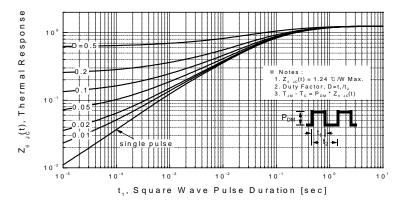
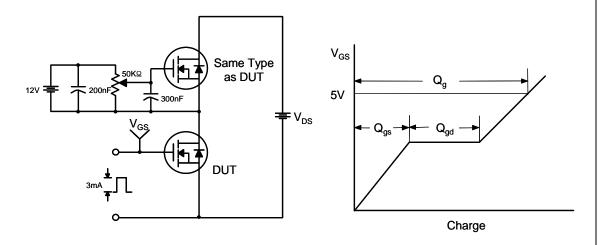


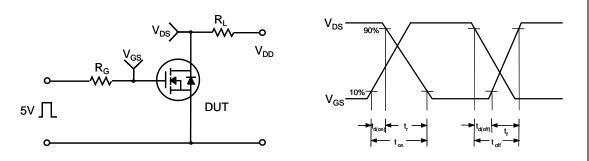
Figure 11. Transient Thermal Response Curve

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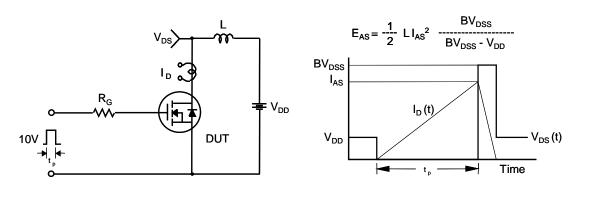
Gate Charge Test Circuit & Waveform



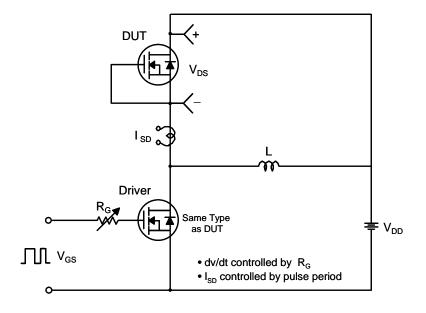
Resistive Switching Test Circuit & Waveforms



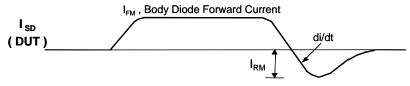
Unclamped Inductive Switching Test Circuit & Waveforms



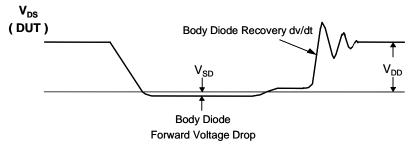
Peak Diode Recovery dv/dt Test Circuit & Waveforms





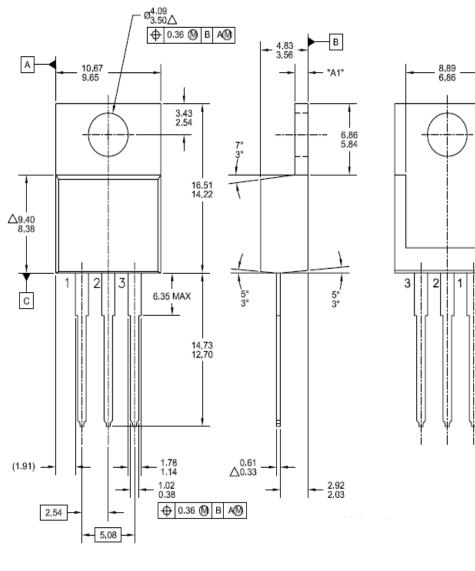


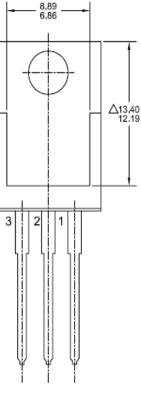
Body Diode Reverse Current

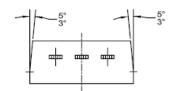




TO - 220







Dimensions in Millimeters

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